Announcing the Final Examination of Eric Schneller for the degree of Doctor of Philosophy

Time & Location: November 9, 2016 at 10:00 AM in CREOL 103
Title: Advanced Metrology and Diagnostic Loss Analytics for Crystalline Silicon Photovoltaics

Characterization plays a key role in developing a comprehensive understanding of the structure and performance of photovoltaic devices. High quality characterization methods enable researchers to assess material choices and processing steps, ultimately giving way to improved device performance and reduced manufacturing costs. In this work, several aspects of advanced metrology for crystalline silicon photovoltaic are investigated including in-line applications for manufacturing, off-line applications for research and development, and module/system level applications to evaluate long-term reliability.

A framework was developed to assess the cost and potential value of metrology within a manufacturing line. This framework has been published to an online calculator in an effort to provide the solar industry with an intuitive and transparent method of evaluating the economics of in-line metrology. One important use of metrology is in evaluating spatial uniformities, as localized defects in large area solar cells often reduce overall device performance. Techniques that probe spatial uniformity were explored and analysis algorithms were developed that provide insights regarding process uniformity and its impact on device performance. Finally, a comprehensive suite of module level characterization was developed to accurately evaluate performance and identify degradation mechanisms in field deployed photovoltaic modules. For each of these applications, case studies were used to demonstrate the value of these techniques and to highlight potential use cases.

Major: Materials Science and Engineering

Educational Career:
Bachelor's of Physics, BS, 2010, Point Loma Nazarene University
Master's of Material Science and Engineering, MS, 2012, University of Central Florida

Committee in Charge:
Winston Schoenfeld, Chair, Material Science and Engineering
Jayan, Thomas, Material Science and Engineering
Kevin, Coffey, Material Science and Engineering
James, Fenton, Material Science and Engineering
Kalpathy, Sundaram, Electrical Engineering and Computer Science

Approved for distribution by Winston Schoenfeld, Committee Chair, on October 21, 2016.

The public is welcome to attend.